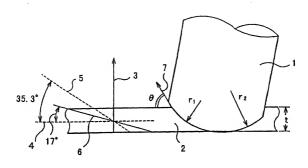
APPLN. FILING DATE: AUGUST 22, 2003
TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING IMPROVED TIP PORTION

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

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FIG. 1A





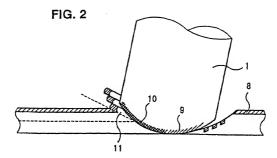


APPLN. FILING DATE: AUGUST 22, 2003
TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

IMPROVED TIP PORTION

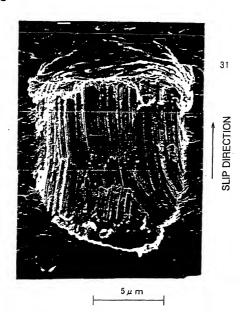
INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

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IMPROVED TIP PORTION
INVENTOR(S): TAKEMOTO ETAL
APPLICATION SERIAL NO: N/A
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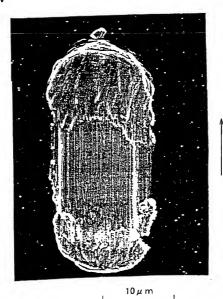
FIG. 3



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INVENTOR(S): TAKEMOTO ETAL
APPLICATION SERIAL NO: N/A
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FIG. 4



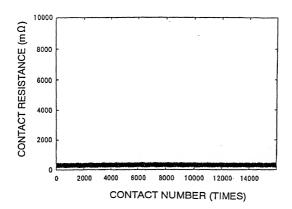
SLIP DIRECTION

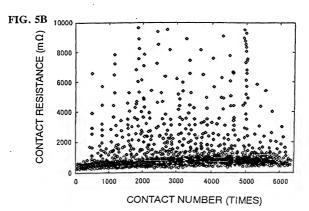
APPLN. FILING DATE: AUGUST 22, 2003
TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING
IMPROVED TIP PORTION

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

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FIG. 5A



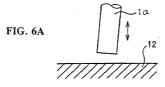


TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

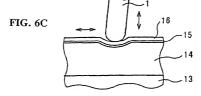
IMPROVED TIP PORTION

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

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TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING
IMPROVED TIP PORTION

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

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FIG. 7

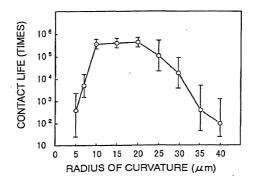
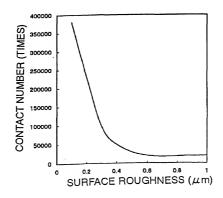


FIG. 8



TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

IMPROVED TIP PORTION

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

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FIG. 9A

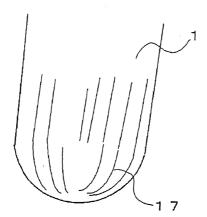
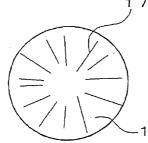


FIG. 9B

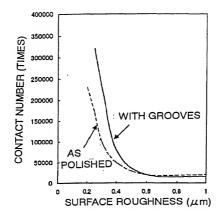


TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

IMPROVED TIP PORTION
INVENTOR(S): TAKEMOTO ETAL
APPLICATION SERIAL NO: N/A

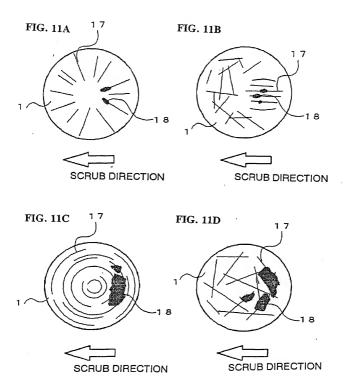
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FIG. 10



TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING IMPROVED TIP PORTION.

INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A SHEET 10 of 13



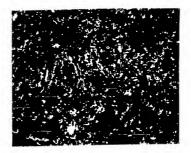
APPLN. FILING DATE: AUGUST 22, 2003 TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING IMPROVED TIP PORTION INVENTOR(S): TAKEMOTO ETAL
APPLICATION SERIAL NO: N/A
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FIG. 12A



 $1 \mu m$

FIG. 12B



 $1 \mu m$

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INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

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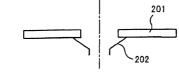
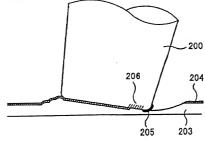


FIG. 13B



APPLN. FILING DATE: AUGUST 22, 2003 TITLE: SEMICONDUCTOR DEVICE TEST PROBE HAVING

IMPROVED TIP PORTION INVENTOR(S): TAKEMOTO ETAL APPLICATION SERIAL NO: N/A

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FIG. 14

